TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC74AC573P,TC74AC573F,TC74AC573FT

#### Octal D-Type Latch with 3-State Output

The TC74AC573 is an advanced high speed CMOS OCTAL LATCH fabricated with silicon gate and double-layer metal wiring  $C^2MOS$  technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

These 8-bit D-type latches are controlled by a latch enable input (LE) and a output enable input ( $\overline{OE}$ ).

When the  $\overline{OE}$  input is high, the eight outputs are in a high impedance state.

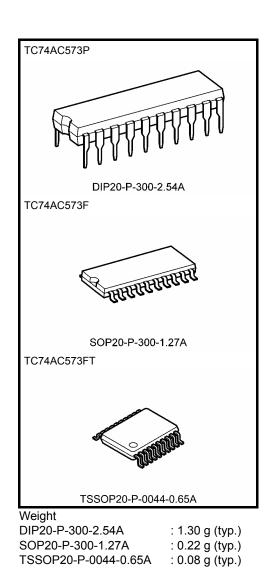
All inputs are equipped with protection circuits against static discharge or transient excess voltage.

### Features

- High speed:  $t_{pd} = 6.0$  ns (typ.) at  $V_{CC} = 5$  V
- Low power dissipation:  $I_{CC} = 8 \mu A \pmod{at Ta} = 25^{\circ}C$
- High noise immunity: V<sub>NIH</sub> = V<sub>NIL</sub> = 28% V<sub>CC</sub> (min)
- Symmetrical output impedance:  $|I_{OH}| = I_{OL} = 24 \text{ mA} \text{ (min)}$

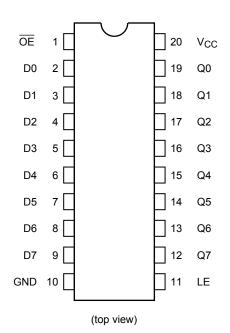
Capability of driving 50  $\Omega$  transmission lines.

- Balanced propagation delays:  $t_{pLH} \simeq t_{pHL}$
- Wide operating voltage range: VCC (opr) = 2 to 5.5 V
- Pin and function compatible with 74F573



# <u>TOSHIBA</u>

## **Pin Assignment**



## **IEC Logic Symbol**

OE(1) _⊾ LE(11)	EN C1		
D0 (2) D1 (3) D2 (4) D3 (5) D4 (6) D5 (7) D6 (8) D7 (9)	1D	▽	(19) Q0 (18) Q1 (17) Q2 (16) Q3 (15) Q4 (14) Q5 (13) Q6 (12) Q7

### Truth Table

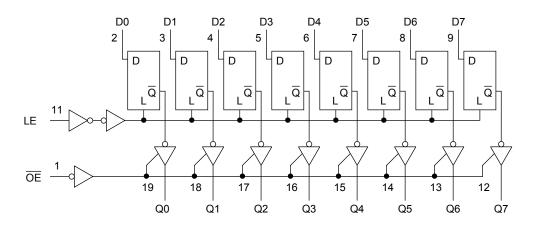
	Inputs	Output			
ŌĒ	LE	D	Q		
Н	Х	Х	Z		
L	L	Х	Qn		
L	Н	L	L		
L	Н	Н	Н		

X: Don't care

Z: High impedance

 $\mathsf{Q}_n:\mathsf{Q}$  outputs are latched at the time when the LE input is taken to a low logic level.

## System Diagram



### Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V <sub>CC</sub>	-0.5 to 7.0	V
DC input voltage	VIN	-0.5 to V <sub>CC</sub> + 0.5	V
DC output voltage	V <sub>OUT</sub>	-0.5 to V <sub>CC</sub> + 0.5	V
Input diode current	I <sub>IK</sub>	±20	mA
Output diode current	IOK	±50	mA
DC output current	IOUT	±50	mA
DC V <sub>CC</sub> /ground current	ICC	±200	mA
Power dissipation	PD	500 (DIP) (Note 2)/180 (SOP/TSSOP)	mW
Storage temperature	T <sub>stg</sub>	−65 to 150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of Ta = -40 to  $65^{\circ}$ C. From Ta = 65 to  $85^{\circ}$ C a derating factor of -10 mW/°C should be applied up to 300 mW.

Characteristics	Symbol	Rating	Unit	
Supply voltage	V <sub>CC</sub>	2.0 to 5.5	V	
Input voltage	V <sub>IN</sub>	0 to V <sub>CC</sub>	V	
Output voltage	V <sub>OUT</sub>	0 to V <sub>CC</sub>	V	
Operating temperature	T <sub>opr</sub>	-40 to 85	°C	
Input rise and fall time	dt/dV	0 to 100 (V <sub>CC</sub> = $3.3 \pm 0.3$ V)	ns/V	
	u/uv	0 to 20 (V <sub>CC</sub> = 5 $\pm$ 0.5 V)	ns/v	

#### **Operating Ranges (Note)**

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

### **Electrical Characteristics**

#### **DC Characteristics**

Characteristics	ristics Symbol			-	Га = 25°(	)	Ta = −40 to 85°C		Unit		
Characteristics	Symbol			V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	Onic	
			2.0	1.50	_	_	1.50	_			
High-level input voltage	VIH			3.0	2.10	_	_	2.10	_	V	
			5.5	3.85	—	_	3.85	—			
					2.0	_	_	0.50	_	0.50	
Low-level input voltage	VIL		_		3.0	_	—	0.90	_	0.90	V
					5.5	—	—	1.65	—	1.65	
					2.0	1.9	2.0	_	1.9	_	
			I <sub>OH</sub> = −50 µA		3.0	2.9	3.0	_	2.9	—	
High-level output	Varia	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>			4.5	4.4	4.5	_	4.4	—	V
voltage	V <sub>OH</sub>		I <sub>OH</sub> = −4 mA		3.0	2.58	_	_	2.48	_	
			I <sub>OH</sub> = −24 mA		4.5	3.94	—	_	3.80	—	
			I <sub>OH</sub> = −75 mA	(Note)	5.5	—	—	—	3.85	—	
					2.0	_	0.0	0.1	_	0.1	- V
			I <sub>OL</sub> = 50 μA		3.0	—	0.0	0.1	—	0.1	
Low-level output	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or			4.5	—	0.0	0.1	—	0.1	
voltage	VOL	VIL	I <sub>OL</sub> = 12 mA		3.0	_	_	0.36	_	0.44	
			I <sub>OL</sub> = 24 mA		4.5	—	—	0.36	—	0.44	
			I <sub>OL</sub> = 75 mA	(Note)	5.5	—	—	—	—	1.65	
3-state output off-state current	I <sub>OZ</sub>	V <sub>IN</sub> = V <sub>IF</sub> V <sub>OUT</sub> = \	<sub>H</sub> or V <sub>IL</sub> / <sub>CC</sub> or GND		5.5	_	_	±0.5	_	±5.0	μA
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND		5.5	_	_	±0.1	I	±1.0	μA	
Quiescent supply current	ICC	V <sub>IN</sub> = V <sub>C</sub>	<sub>C</sub> or GND		5.5	_	_	8.0	_	80.0	μA

Note: This spec indicates the capability of driving 50  $\Omega$  transmission lines.

One output should be tested at a time for a 10 ms maximum duration.

#### Timing Requirements (input: $t_r = t_f = 3 \text{ ns}$ )

Characteristics	Characteristics Symbol Test Condition			Ta = 25°C	Ta = −40 to 85°C	Unit
			$V_{CC}(V)$	Limit	Limit	
Minimum pulse width	<b>t</b> an		3.3 ± 0.3	7.0	7.0	20
(LE)	<sup>t</sup> w (H)	—	5.0 ± 0.5	5.0	5.0	ns
Minimum set-up time			$3.3 \pm 0.3$	7.0	7.0	ns
Minimum set-up time	ts	—	5.0 ± 0.5	4.0	4.0	
Minimum hold time	<b>t</b> .		$3.3 \pm 0.3$	1.0	1.0	ns
	t <sub>h</sub>	—	5.0 ± 0.5	1.0	1.0	

#### AC Characteristics (C<sub>L</sub> = 50 pF, R<sub>L</sub> = 500 $\Omega$ , input: t<sub>r</sub> = t<sub>f</sub> = 3 ns)

Characteristics	Symbol Test Condition			Ta = 25°C				Ta = −40 to 85°C	
	- ,		V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	
Propagation delay time	t <sub>pLH</sub>	_	3.3 ± 0.3	_	9.4	15.4	1.0	17.6	ns
(LE-Q)	t <sub>pHL</sub>		5.0 ± 0.5	—	6.6	9.9	1.0	11.3	110
Propagation delay time	t <sub>pLH</sub>	_	3.3 ± 0.3		9.4	16.0	1.0	18.2	ns
(Dn-Q)	t <sub>pHL</sub>		5.0 ± 0.5	—	6.2	8.9	1.0	10.2	
Output enable time	t <sub>pZL</sub>		3.3 ± 0.3		9.0	15.2	1.0	17.3	20
	t <sub>pZH</sub>	—	5.0 ± 0.5		6.3	9.2	1.0	10.5	ns
Output disable time	t <sub>pLZ</sub>		3.3 ± 0.3		7.0	12.3	1.0	14.0	ns
	t <sub>pHZ</sub>	_	$5.0 \pm 0.5$	—	6.0	8.8	1.0	10.0	115
Input capacitance	CIN	—		_	5	10	-	10	pF
Output capacitance	C <sub>OUT</sub>	_		_	10	_	_	_	pF
Power dissipation capacitance	C <sub>PD</sub>		(Note)		32	l		_	pF

Note: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/8$  (per latch)

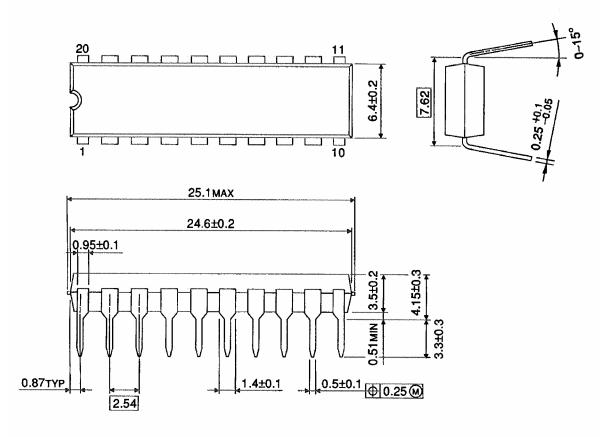
And the total  $C_{PD}$  when n pcs. of latch operate can be gained by the following equation:

C<sub>PD</sub> (total) = 21 + 11·n

#### **Package Dimensions**

DIP20-P-300-2.54A

Unit : mm



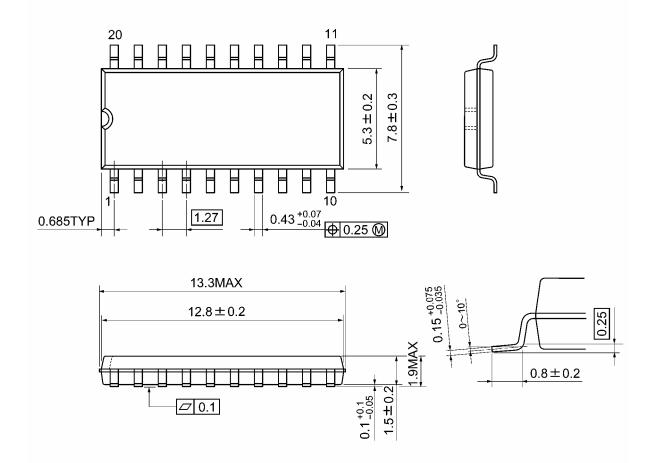
Weight: 1.30 g (typ.)

# **TOSHIBA**

## Package Dimensions

SOP20-P-300-1.27A

Unit: mm



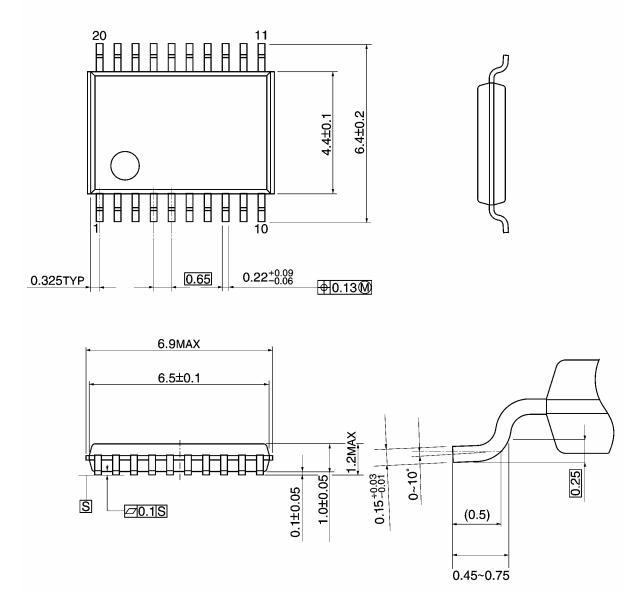
Weight: 0.22 g (typ.)

# **TOSHIBA**

## Package Dimensions

TSSOP20-P-0044-0.65A

Unit: mm



Weight: 0.08 g (typ.)

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20070701-EN GENERAL

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